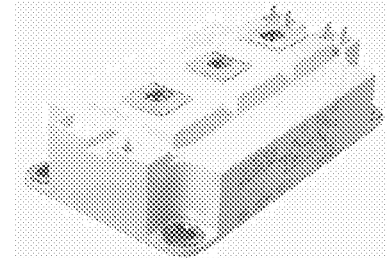


Absolute Maximum Ratings		Values		Units
Symbol	Conditions ¹⁾	... 123 D	... 123 D1	
V_{CES}		1200		V
V_{CGR}	$R_{GE} = 20 \text{ k}\Omega$	1200		V
I_C	$T_{case} = 25/80 \text{ }^\circ\text{C}$	200 / 180		A
I_{CM}	$T_{case} = 25/80 \text{ }^\circ\text{C}; t_p = 1 \text{ ms}$	400 / 360		A
V_{GES}		± 20		V
P_{tot}	per IGBT, $T_{case} = 25 \text{ }^\circ\text{C}$	1380		W
T_{Jj} (T_{stg})		$-40 \dots +150$ (125)		$^\circ\text{C}$
V_{isol}	AC, 1 min.	2 500 ⁷⁾		V
humidity	DIN 40 040	Class F		
climate	DIN IEC 68 T.1	40/125/56		
Inverse Diode			FWD ⁶⁾	
$I_F = -I_C$	$T_{case} = 25/80 \text{ }^\circ\text{C}$	200 / 130	260 / 180	A
$I_{FM} = -I_{CM}$	$T_{case} = 25/80 \text{ }^\circ\text{C}; t_p = 1 \text{ ms}$	400 / 360	400 / 360	A
I_{FSM}	$t_p = 10 \text{ ms}; \sin.; T_J = 150 \text{ }^\circ\text{C}$	1450	1800	A
I_t^2	$t_p = 10 \text{ ms}; T_J = 150 \text{ }^\circ\text{C}$	10 500	24 200	A ² s

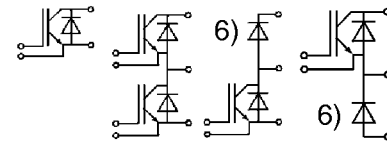
Characteristics		min.	typ.	max.	Units
Symbol	Conditions ¹⁾				
$V_{(BR)CES}$	$V_{GE} = 0, I_C = 4 \text{ mA}$	$\geq V_{CES}$	—	—	V
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 6 \text{ mA}$	4,5	5,5	6,5	V
I_{CES}	$V_{GE} = 0 \quad \left. \begin{array}{l} T_J = 25 \text{ }^\circ\text{C} \\ T_J = 125 \text{ }^\circ\text{C} \end{array} \right\}$	—	0,2	3	mA
	$V_{CE} = V_{CES}$	—	12	—	
I_{GES}	$V_{GE} = 20 \text{ V}, V_{CE} = 0$	—	—	1	μA
V_{CEsat}	$I_C = 150 \text{ A} \quad \left. \begin{array}{l} V_{GE} = 15 \text{ V;} \\ T_J = 25 (125) \text{ }^\circ\text{C} \end{array} \right\}$	—	2,5(3,1)	3(3,7)	V
V_{CEsat}	$I_C = 200 \text{ A} \quad \left. \begin{array}{l} V_{GE} = 15 \text{ V;} \\ T_J = 25 (125) \text{ }^\circ\text{C} \end{array} \right\}$	—	2,8(3,6)	—	V
g_{fs}	$V_{GE} = 20 \text{ V}, I_C = 150 \text{ A}$	95	—	—	S
C_{CHC}	per IGBT	—	—	700	pF
C_{ies}	$V_{GE} = 0$	—	10	13	nF
C_{oes}	$V_{CE} = 25 \text{ V}$	—	1,5	2	nF
C_{res}	$f = 1 \text{ MHz}$	—	0,8	1,2	nF
L_{CE}		—	—	20	nH
$t_{d(on)}$	$V_{CC} = 600 \text{ V}$	—	220	400	ns
t_r	$V_{GE} = -15 \text{ V} / +15 \text{ V}^{3)}$	—	100	200	ns
$t_{d(off)}$	$I_C = 150 \text{ A}, \text{ ind. load}$	—	600	800	ns
t_f	$R_{Gon} = R_{Goff} = 5,6 \text{ } \Omega$	—	70	100	ns
$E_{on}^{5)}$	$T_J = 125 \text{ }^\circ\text{C}$	—	24	—	mWs
$E_{off}^{5)}$		—	17	—	mWs
Inverse Diode ⁸⁾					
$V_F = V_{EC}$	$I_F = 150 \text{ A} \quad \left. \begin{array}{l} V_{GE} = 0 \text{ V;} \\ T_J = 25 (125) \text{ }^\circ\text{C} \end{array} \right\}$	—	2,0(1,8)	2,5	V
$V_F = V_{EC}$	$I_F = 200 \text{ A} \quad \left. \begin{array}{l} V_{GE} = 0 \text{ V;} \\ T_J = 25 (125) \text{ }^\circ\text{C} \end{array} \right\}$	—	2,25(2,05)	—	V
V_{TO}	$T_J = 125 \text{ }^\circ\text{C}$	—	—	1,2	V
r_T	$T_J = 125 \text{ }^\circ\text{C}$	—	5	7	m Ω
I_{RRM}	$I_F = 150 \text{ A}; T_J = 25 (125) \text{ }^\circ\text{C}^{2)}$	—	55(80)	—	A
Q_{rr}	$I_F = 150 \text{ A}; T_J = 25 (125) \text{ }^\circ\text{C}^{2)}$	—	8(20)	—	μC
FWD of types "GAL", "GAR" "123D1" ⁸⁾ ⁶⁾					
$V_F = V_{EC}$	$I_F = 150 \text{ A} \quad \left. \begin{array}{l} V_{GE} = 0 \text{ V;} \\ T_J = 25 (125) \text{ }^\circ\text{C} \end{array} \right\}$	—	1,85(1,6)	2,2	V
$V_F = V_{EC}$	$I_F = 200 \text{ A} \quad \left. \begin{array}{l} V_{GE} = 0 \text{ V;} \\ T_J = 25 (125) \text{ }^\circ\text{C} \end{array} \right\}$	—	2,0(1,8)	—	V
V_{TO}	$T_J = 125 \text{ }^\circ\text{C}$	—	—	1,2	V
r_T	$T_J = 125 \text{ }^\circ\text{C}$	—	3	5,5	m Ω
I_{RRM}	$I_F = 150 \text{ A}; T_J = 25 (125) \text{ }^\circ\text{C}^{2)}$	—	60(90)	—	A
Q_{rr}	$I_F = 150 \text{ A}; T_J = 25 (125) \text{ }^\circ\text{C}^{2)}$	—	8(23)	—	μC
Thermal Characteristics					
R_{thjc}	per IGBT	—	—	0,09	$^\circ\text{C/W}$
R_{thjc}	per diode / FWD "GAL; GAR"	—	—	0,25/0,18	$^\circ\text{C/W}$
R_{thch}	per module	—	—	0,038	$^\circ\text{C/W}$

SEMITRANS® M IGBT Modules

SKM 200 GA 123 D ^{*)}
 SKM 200 GB 123 D
 SKM 200 GB 123 D1 ⁶⁾
 SKM 200 GAL 123 D ⁶⁾
 SKM 200 GAR 123 D ⁶⁾



SEMITRANS 3



GA GB GAL GAR

Features

- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to $6 \cdot I_{cnom}$
- Latch-up free
- Fast & soft inverse CAL diodes ⁸⁾
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (13 mm) and creepage distances (20 mm).

Typical Applications: → B6 - 153

- Switching (not for linear use)

¹⁾ $T_{case} = 25 \text{ }^\circ\text{C}$, unless otherwise specified

²⁾ $I_F = -I_C, V_R = 600 \text{ V}, -di_F/dt = 1500 \text{ A}/\mu\text{s}, V_{GE} = 0 \text{ V}$

³⁾ Use $V_{GEoff} = -5 \dots -15 \text{ V}$

⁵⁾ See fig. 2 + 3; $R_{Goff} = 5,6 \text{ } \Omega$

⁶⁾ The free-wheeling diodes of the GAL and GAR types have the data of the inverse diodes of SKM 300 GA 123 D

⁷⁾ $V_{isol} = 4000 \text{ V}_{rms}$ on request

⁸⁾ CAL = Controlled Axial Lifetime Technology.

Cases and mech. data → B6-154

*) SEMITRANS 4 → B6-168

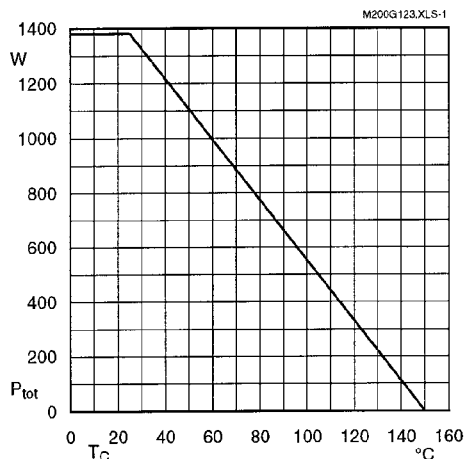


Fig. 1 Rated power dissipation $P_{tot} = f(T_C)$

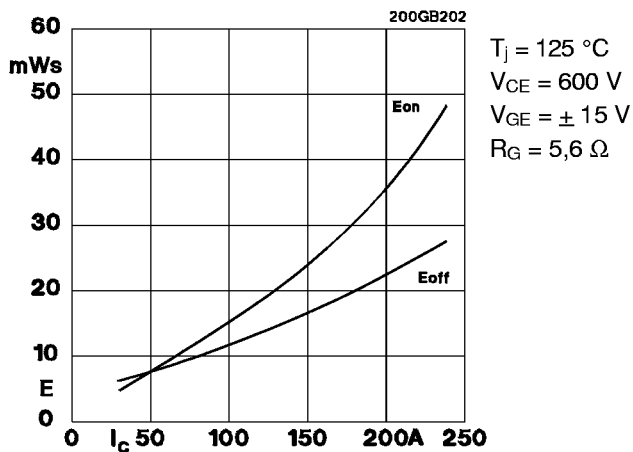


Fig. 2 Turn-on /-off energy = $f(I_C)$

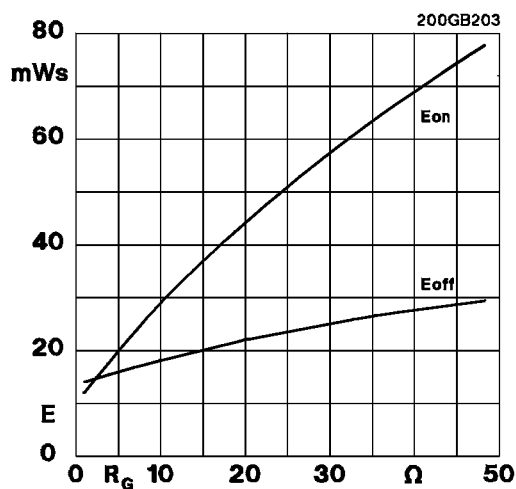


Fig. 3 Turn-on /-off energy = $f(R_G)$

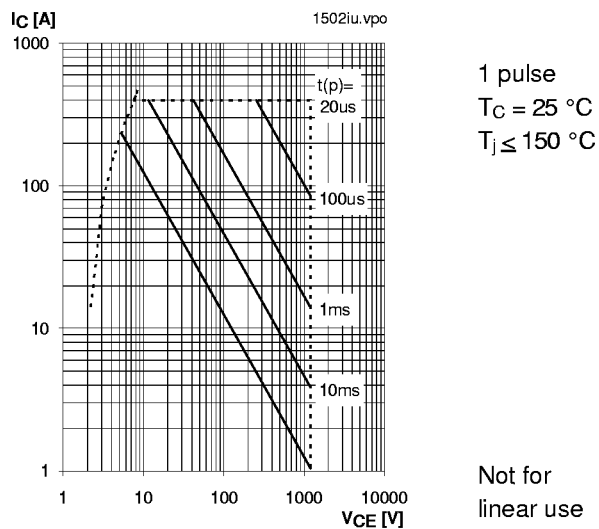


Fig. 4 Maximum safe operating area (SOA) $I_C = f(V_{CE})$

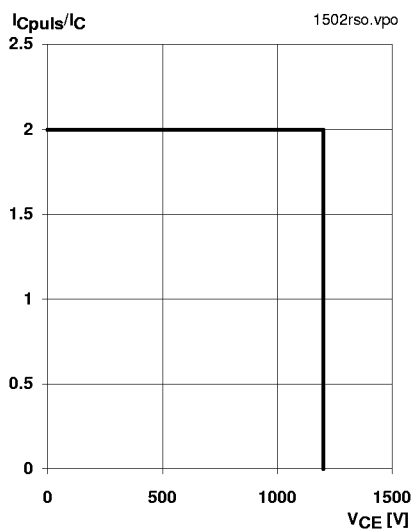


Fig. 5 Turn-off safe operating area (RBSOA)

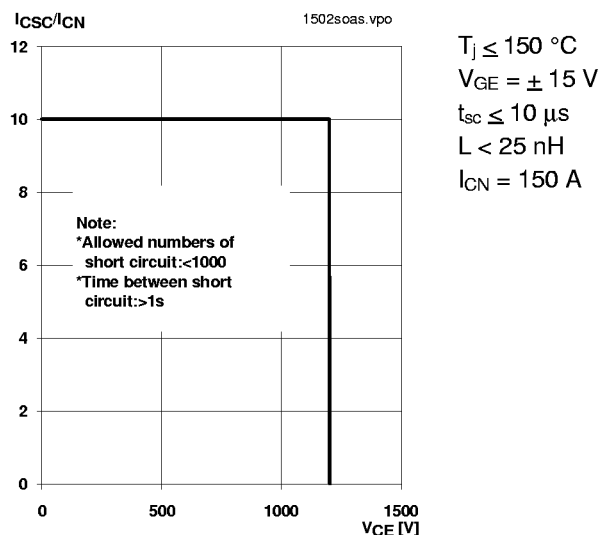


Fig. 6 Safe operating area at short circuit $I_C = f(V_{CE})$

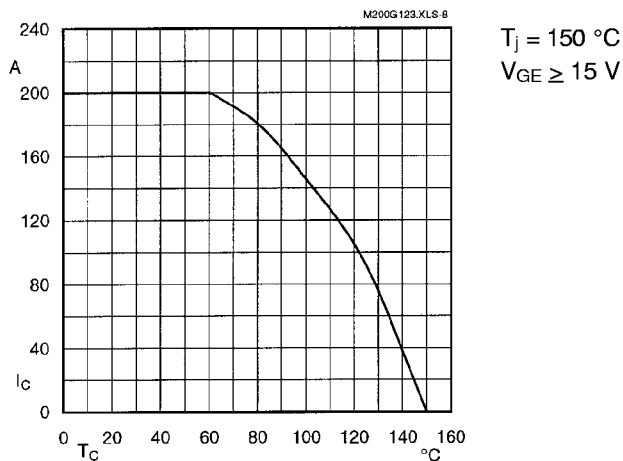


Fig. 8 Rated current vs. temperature $I_C = f(T_C)$

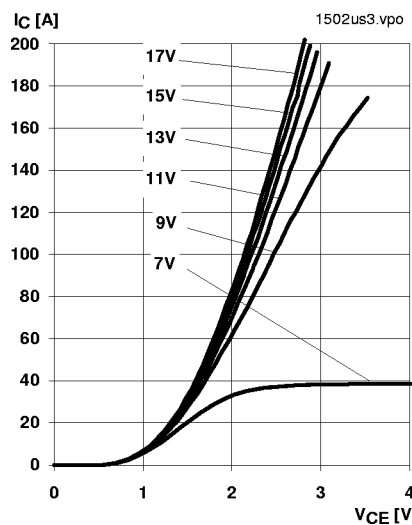


Fig. 9 Typ. output characteristic, $t_p = 80$ μs; 25 °C

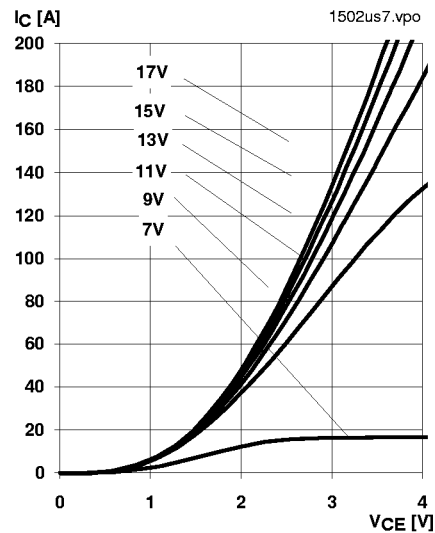


Fig. 10 Typ. output characteristic, $t_p = 80$ μs; 125 °C

$$P_{cond(t)} = V_{CEsat(t)} \cdot I_{C(t)}$$

$$V_{CEsat(t)} = V_{CE(TO)(T_j)} + r_{CE(T_j)} \cdot I_{C(t)}$$

$$V_{CE(TO)(T_j)} \leq 1,5 + 0,002 (T_j - 25) [V]$$

$$\text{typ.: } r_{CE(T_j)} = 0,0066 + 0,000027 (T_j - 25) [\Omega]$$

$$\text{max.: } r_{CE(T_j)} = 0,0100 + 0,000033 (T_j - 25) [\Omega]$$

$$\text{valid for } V_{GE} = +15 \frac{+2}{-1} [V]; I_C > 0,3 I_{Cnom}$$

Fig. 11 Saturation characteristic (IGBT)
Calculation elements and equations

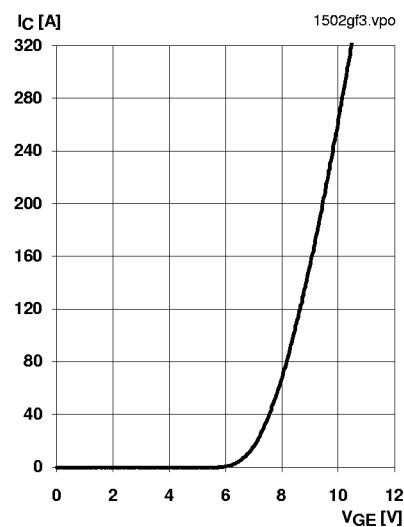


Fig. 12 Typ. transfer characteristic, $t_p = 80$ μs; $V_{CE} = 20$ V

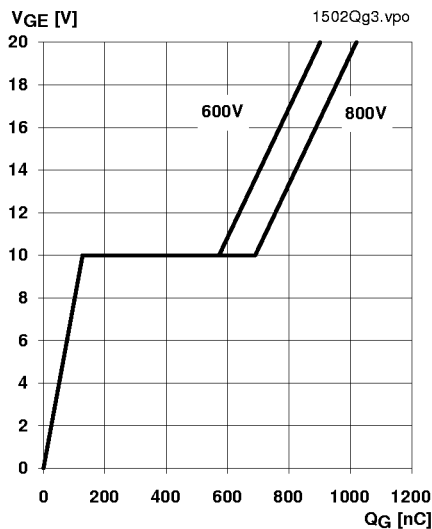


Fig. 13 Typ. gate charge characteristic

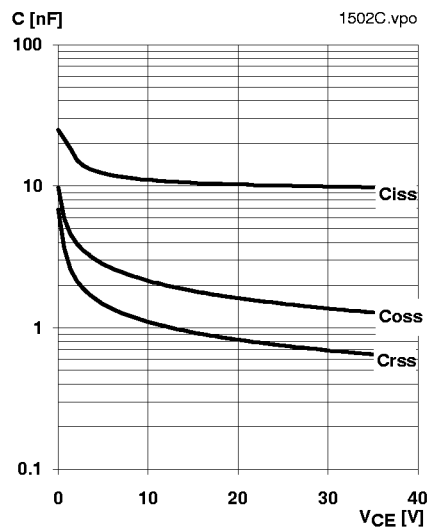


Fig. 14 Typ. capacitances vs. V_{CE}

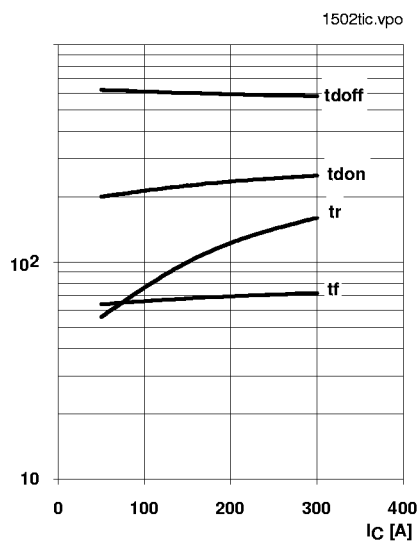


Fig. 15 Typ. switching times vs. I_C

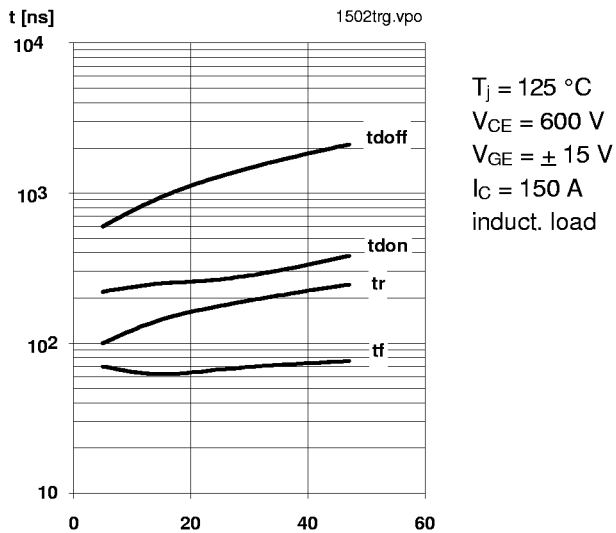


Fig. 16 Typ. switching times vs. gate resistor R_G

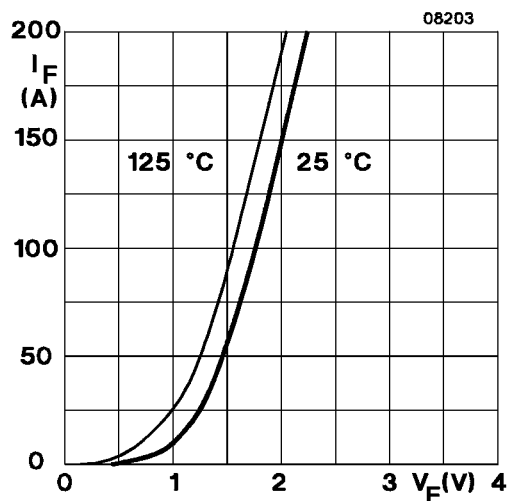


Fig. 17 Typ. CAL diode forward characteristic

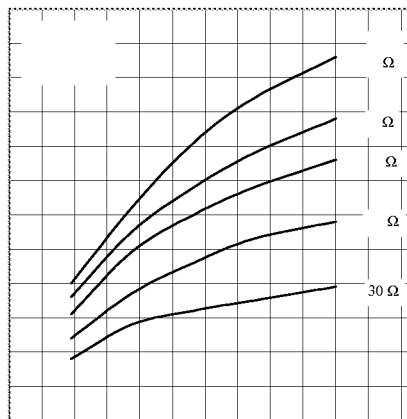


Fig. 18 Diode turn-off energy dissipation per pulse

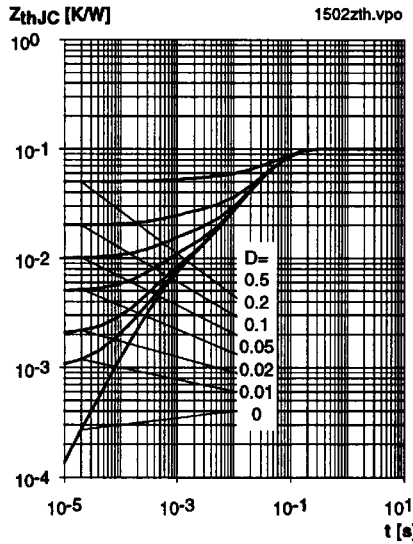


Fig. 19 Transient thermal impedance of IGBT
 $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

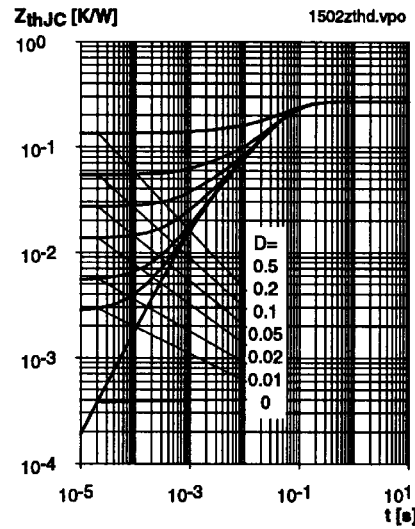


Fig. 20 Transient thermal impedance of inverse CAL diodes
 $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

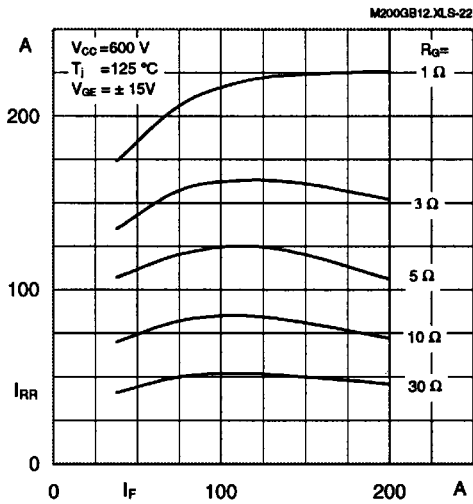


Fig. 22 Typ. CAL diode peak reverse recovery current $I_{RR} = f(I_F, R_G)$

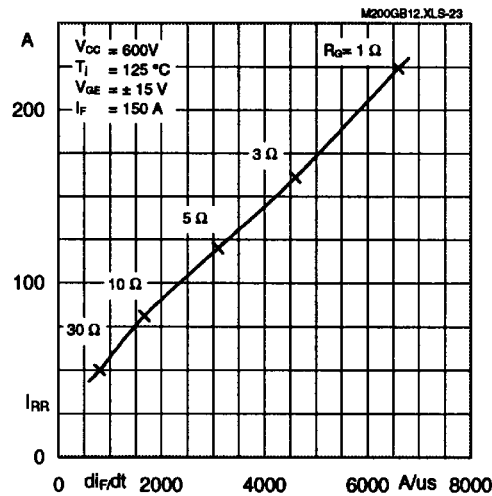


Fig. 23 Typ. CAL diode peak reverse recovery current $I_{RR} = f(dI_F/dt)$

Typical Applications

include

- Switched mode power supplies
- DC servo and robot drives
- Inverters
- DC choppers (versions GAR; GAL)
- AC motor speed control
- Inductive heating
- UPS Uninterruptable power supplies
- General power switching applications

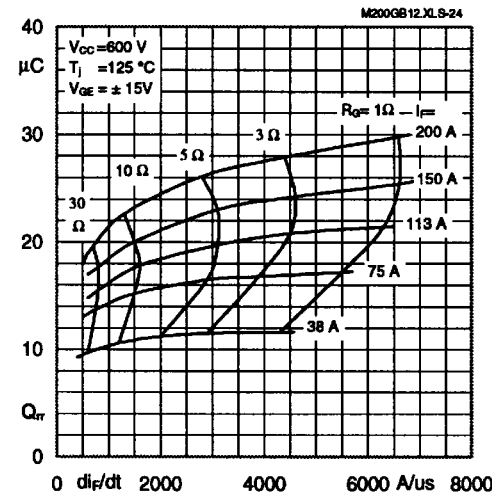
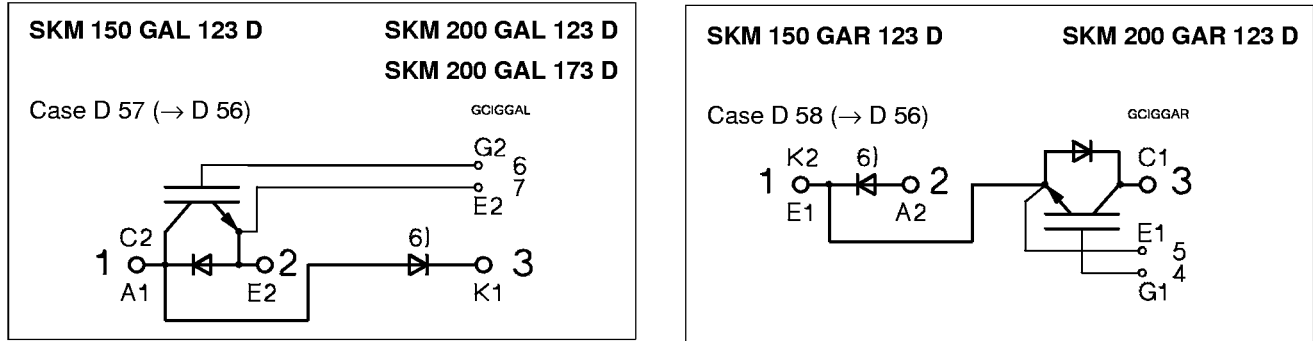
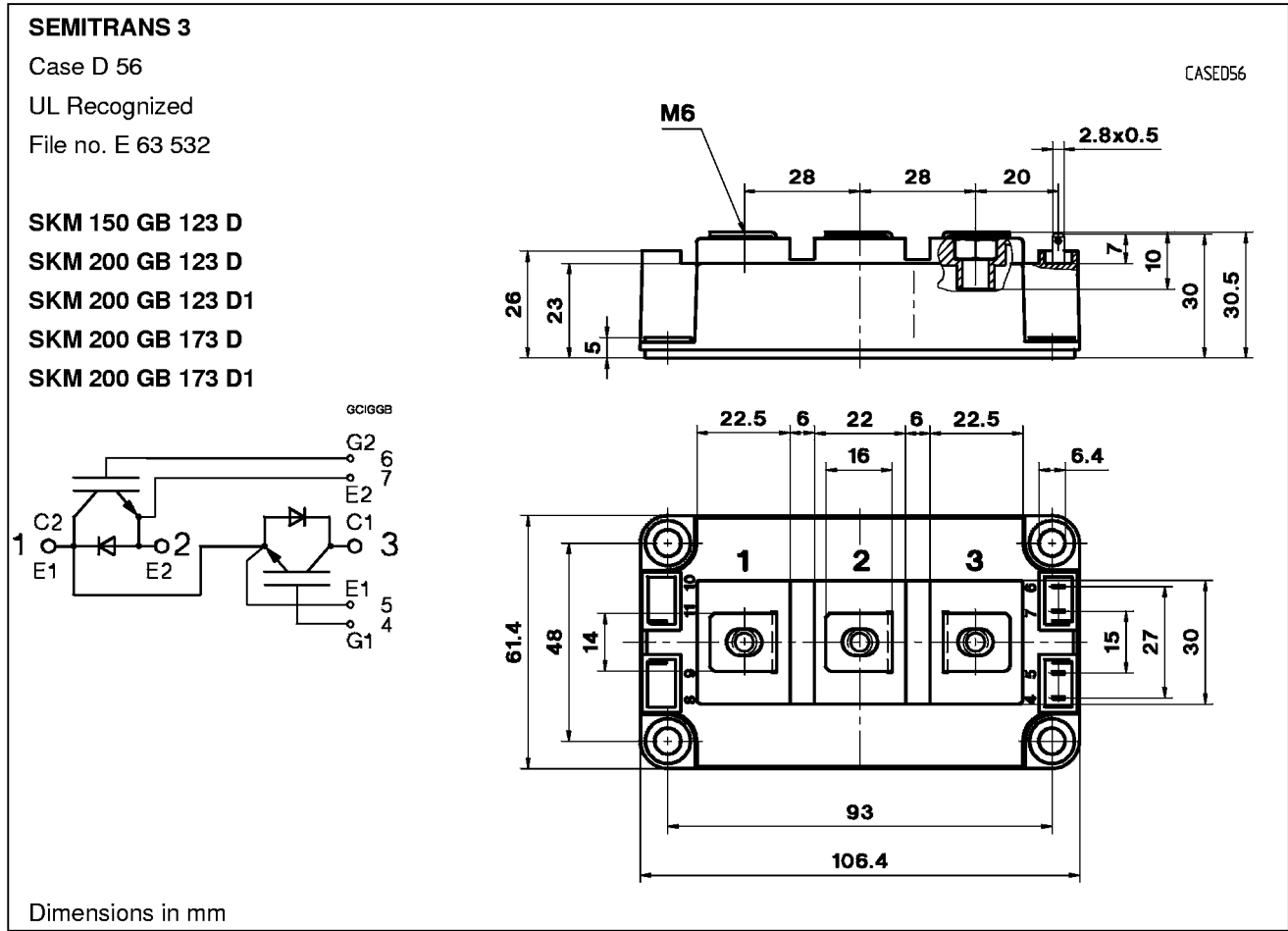


Fig. 24 Typ. CAL diode recovered charge $Q_{RR} = f(dI_F/dt)$



Case outline and circuit diagrams

For SKM 200 GA 123 D (SEMITRANS 4) → B 6 - 168

Mechanical Data			Values			Units
Symbol	Conditions		min.	typ.	max.	
M ₁	to heatsink, SI Units	(M6)	3	—	5	Nm
	to heatsink, US Units		27	—	44	lb.in.
M ₂	for terminals, SI Units	(M6)	2,5	—	5	Nm
	for terminals US Units		22	—	44	lb.in.
a			—	—	5x9,81	m/s ²
w			—	—	325	g

⁶⁾ Freewheeling diode → B 6 - 149, remark 6.

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Three devices are supplied in one SEMIBOX A without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 3). Larger packing units of 12 and 20 pieces are used if suitable
Accessories → B 6 - 4.
SEMIBOX → C - 1.